


<b>Search Notes</b>  	<b>Application/Control No.</b>  10527307	<b>Applicant(s)/Patent Under Reexamination</b>  NISHIO ET AL.
	<b>Examiner</b>  ANISH SIKRI	<b>Art Unit</b>  2143

SEARCHED			
Class	Subclass	Date	Examiner
709	203	3/12/2008	AS

SEARCH NOTES		
Search Notes	Date	Examiner
East Image and Keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO and IBM_TDB (see attached search strategy)	3/12/08	AS
Inventor name and Assignee search in PALM ExPO and EAST	3/12/08	AS
I7 and (request\$4 adj (storage or space or area))	3/12/08	AS

INTERFERENCE SEARCH			
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